



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AO4354**  
**30V N-Channel AlphaMOS**

### General Description

- Latest Trench Power AlphaMOS (αMOS LV) technology
- Very Low RDS(on) at 4.5V<sub>GS</sub>
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

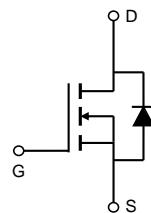
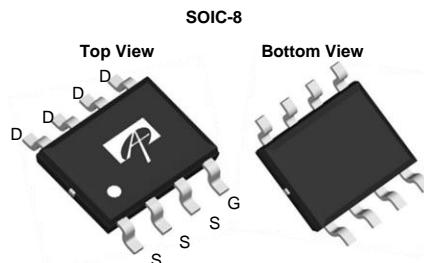
### Application

- DC/DC Converters in Computing, Servers, and POL
- Isolated DC/DC Converters in Telecom and Industrial

### Product Summary

V <sub>DS</sub>	30V
I <sub>D</sub> (at V <sub>GS</sub> =10V)	23A
R <sub>DS(ON)</sub> (at V <sub>GS</sub> =10V)	< 3.7mΩ
R <sub>DS(ON)</sub> (at V <sub>GS</sub> = 4.5V)	< 5.3mΩ

100% UIS Tested  
100% R<sub>g</sub> Tested



### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V <sub>DS</sub>	30	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Continuous Drain Current	I <sub>D</sub>	23	A
T <sub>A</sub> =100°C	14		
Pulsed Drain Current <sup>C</sup>	I <sub>DM</sub>	174	A
Avalanche Current <sup>C</sup>	I <sub>AS</sub>	37	A
Avalanche energy L=0.1mH <sup>C</sup>	E <sub>AS</sub>	68	mJ
V <sub>DS</sub> Spike	V <sub>SPIKE</sub>	36	V
Power Dissipation <sup>B</sup>	P <sub>D</sub>	3.1	W
T <sub>A</sub> =25°C	1.2		
Power Dissipation <sup>B</sup>	T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup> t ≤ 10s	R <sub>θJA</sub>	31	40	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup> Steady-State		59	75	°C/W
Maximum Junction-to-Lead	R <sub>θJL</sub>	16	24	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.2	1.8	2.2	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$	3	3.7	5	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=20\text{A}$	4.1	5	5.3	$\text{m}\Omega$
			4.1		5.3	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		105		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
$I_S$	Maximum Body-Diode Continuous Current				4	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		2010		pF
$C_{oss}$	Output Capacitance			898		pF
$C_{rss}$	Reverse Transfer Capacitance			124		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	0.9	1.8	2.7	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=20\text{A}$		36	49	nC
$Q_g(4.5\text{V})$	Total Gate Charge			17	23	nC
$Q_{gs}$	Gate Source Charge			6		nC
$Q_{gd}$	Gate Drain Charge			8		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=0.75\Omega, R_{\text{GEN}}=3\Omega$		7.5		ns
$t_r$	Turn-On Rise Time			4.0		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			37.0		ns
$t_f$	Turn-Off Fall Time			7.5		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		14		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		20.3		nC

A. The value of  $R_{\text{JJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using  $\leq 10\text{s}$  junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

D. The  $R_{\text{JJA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{JUL}}$  and lead to ambient.

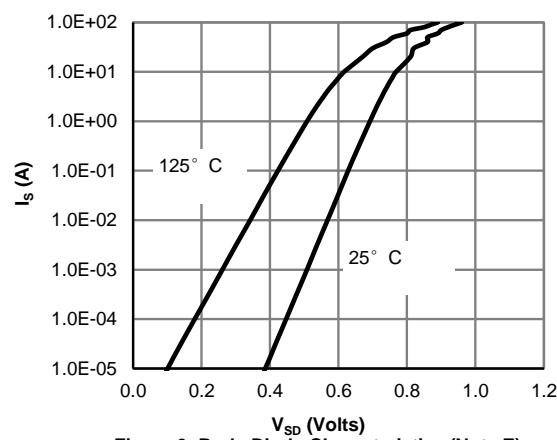
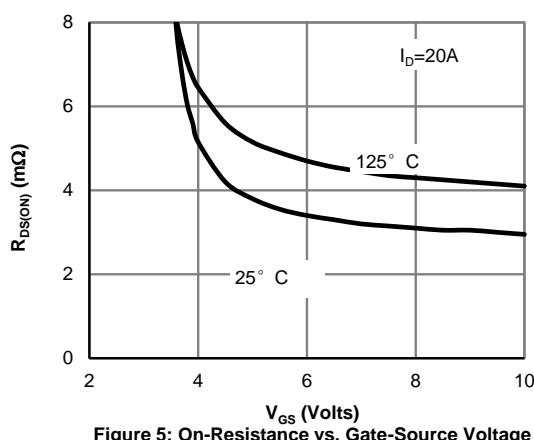
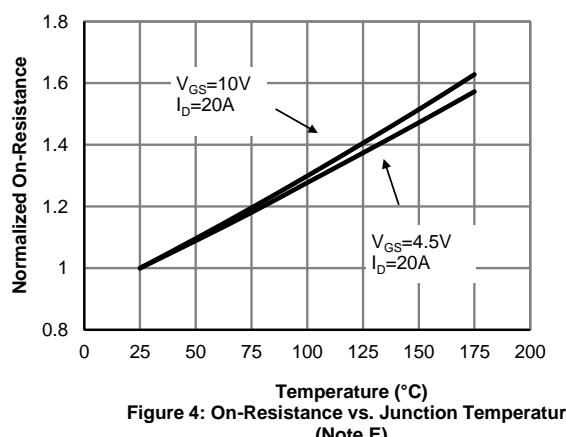
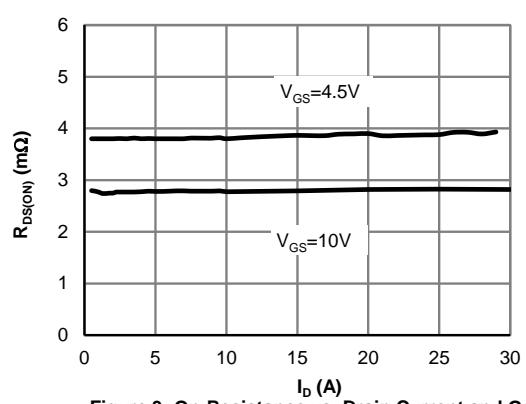
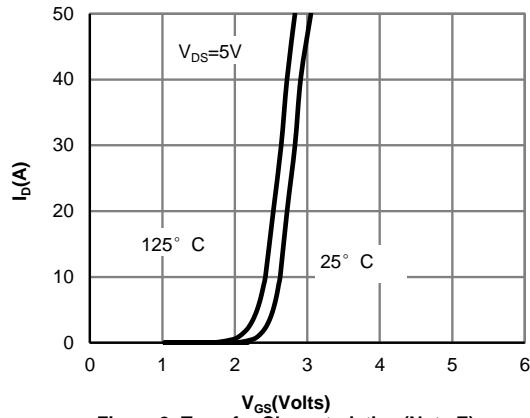
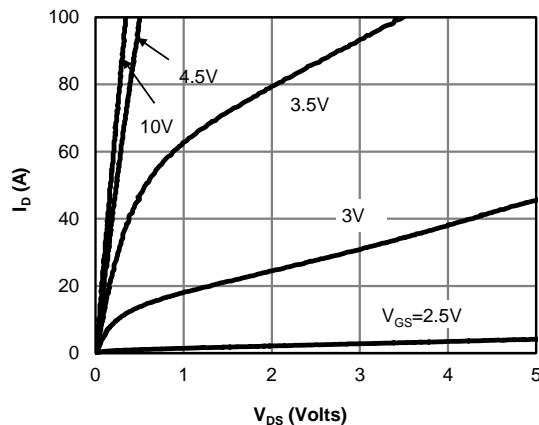
E. The static characteristics in Figures 1 to 6 are obtained using  $<300\mu\text{s}$  pulses, duty cycle 0.5% max.

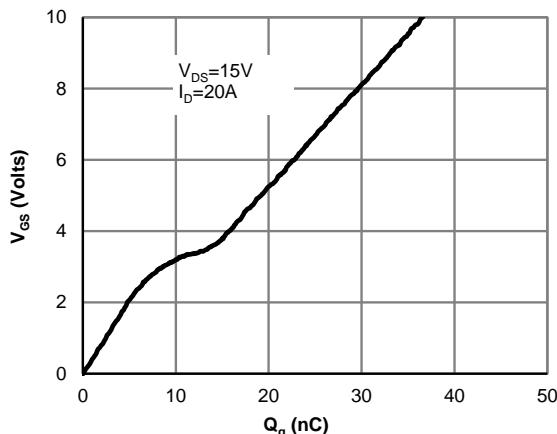
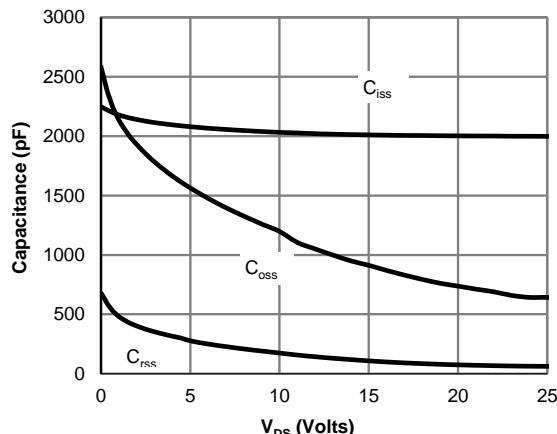
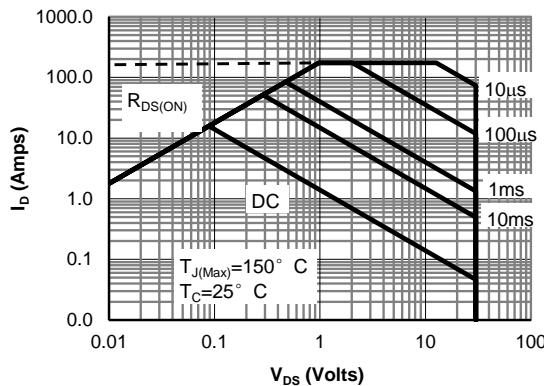
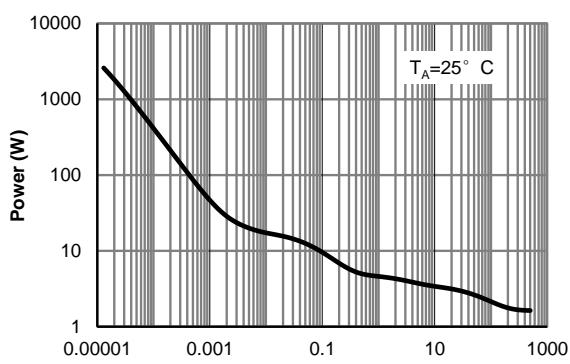
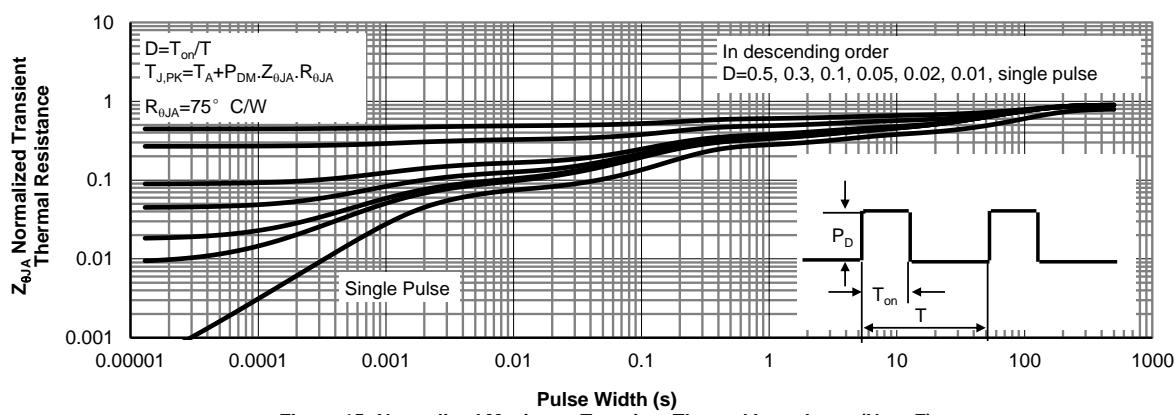
F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

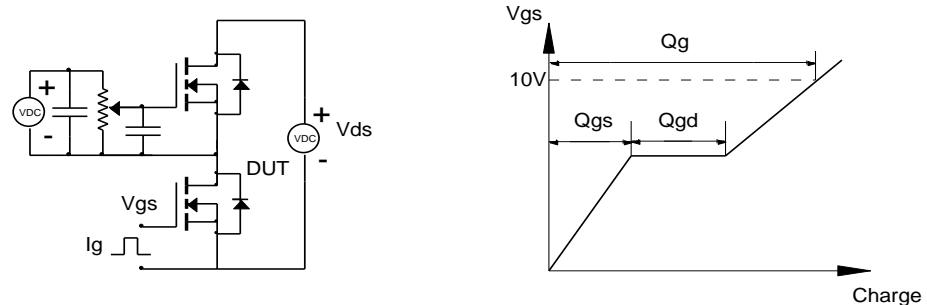
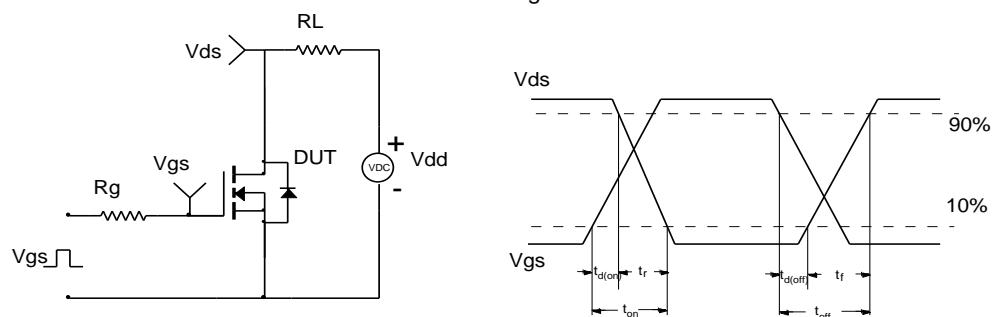
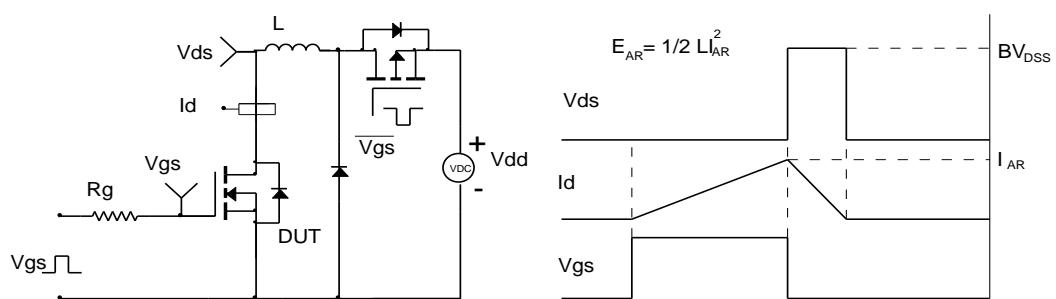
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**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


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**Figure 7: Gate-Charge Characteristics**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area (Note F)**

**Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note F)**

**Figure 15: Normalized Maximum Transient Thermal Impedance (Note F)**

**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**
